



## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

*(Use as many sheets as necessary)*

Sheet	1	of	1
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**Complete if Known**

Application Number	10/717,963
Filing Date	11/21/2003
First Named Inventor	SUMIO ASHIDA
Art Unit	2855 1256
Examiner Name	Unknown <i>Angel</i>
Attorney Docket Number	008312-0306969

## U. S. PATENT DOCUMENTS

**FOREIGN PATENT DOCUMENTS**

Examiner Signature		Date Considered	4/21/06
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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FORM PTO-1449 (modified)  
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Atty.  
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Client Ref.

008312-0306969

T7KO-03S1080

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: ASHIDA et al.

Appin. No.: 10/717,963

Filing Date: November 21, 2003

Date: April 29, 2005

P 1 of 1  
age

Examiner: Unassigned

Group Art Unit: 2655

1756

## U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YY YY	Country	Inventor Name		English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
OR	JP 2001-167475 A	06/2001	Japan	NONAKA et al.		x			
PR	JP 2001-126308 A	05/2001	Japan	ARAI et al.		x			
QR	JP 11-339314 A	12/1999	Japan	NAGINO et al.		x			
RR	JP 03-125343 A	05/1991	Japan	SUZUKI et al.		x			
SR	JP 10-116441 A	05/1998	Japan	ROSEN et al.		x			
TR	JP 2000-339760 A	12/2000	Japan	KUSADA et al.		x			
UR	JP 2001-014723 A	01/2001	Japan	HIROTSUNE et al.		x			
VR	JP 2002-298433 A	10/2002	Japan	YUZUSU et al.		x			
WR						x			
XR									

## OTHER (including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

YR	Japanese Office Action dated March 29, 2005 for Appin. No. 2002-339437
ZR	Japanese Office Action dated March 29, 2005 for Appin. No. 2002-342896
AAR	
BBR	

Examiner

Date Considered:

4/21/06

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Client Ref.

0306969

T7KO-03S1080

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: SUMIO ASHIDA et al.

Appln. No.: UNASSIGNED

Filing Date: November 21, 2003

Examiner: UNKNOWN

Group Art Unit: UNKNOWN

Date: November 21, 2003

Page

1

of

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## U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					

	Document Number	Date MM/YYYY	Country	Inventor Name		Enclosed	No	Enclose	No
<i>u</i>	JR 2003-67974	03/2003	Japan	Inao et al.		X			X
<i>u</i>	KR 2000-322770	11/2000	Japan	Osada et al.		X			X
<i>u</i>	LR 2001-232941	08/2001	Japan	Ashida et al.		X			X
<i>u</i>	MR 11-213446	08/1999	Japan	Ota et al.		X			X
<i>u</i>	NR 2000-222777	08/2000	Japan	Uno et al.		X			X
<i>u</i>	OR 2002-279693	09/2002	Japan	Miyamoto et al.		X			X
	PR 2003-233931	08/2003	Japan		<i>af b</i>		X		X
	QR								
	RR								
	SR								

## OTHER (Including in this order: Author, Title, Periodical Name, Date, Reprint, Pages, etc.)

<i>u</i>	TR	T. Inase et al., "Investigation of Protective Layer for High Transfer Rate Phase Change Optical Disk," Tokyo Research Lab., Tosoh Corp., pages 37-42 (12/2001)							
<i>u</i>	UR	Mayumi Uno et al., "Acceleration of crystallization process by nitride interface layer," Optical Disk Systems Development Center, Matsushita Electric Industrial Co., Ltd., pages 85-90 (11/99)							
<i>u</i>	VR	Rie Kojima et al., "Ge-Sn-Sb-Te Phase-change Recording Material Having High Crystallization Speed," Optical Disk Systems Development Center, Matsushita Electric Industrial Co., Ltd., pages 36-41 (11-12/2000)							
<i>u</i>	WR	Michiaki Shinotsuka et al., "High-speed Blue-laser Recording on the Double-decker Phase Change Disk with High-Reliability," Research and Development Group, Ricoh Company, Ltd., IEEE 2002, pages 234-236 (2002)							
	XR								
	YR								

Examiner

Date Considered:

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